

## **Quarterly Reliability Monitoring Results**

## Quarters: Q1/2021 to Q4/2021

Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		User Part Number BZX8850S-C10 Part Description										
								Nexperia DHAM	Zener			
								MCD package				
		Test Conditions	Duration	# Lots	# Quantity	# Rejects						
			TEST									
			Pre- and Post-Stress									
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below						
		JESD22-A113 Bake Tamb = 125 °C	24 hours									
	PC	Soak Tamb = 125 °C, RH = 85%	168 hours									
# A1	Preconditioning	Reflow soldering	3 cycles	113	9040	0						
		MIL-STD-750-1										
	HTRB	M1038 Method A										
		Tj = Tjmax, Vr = 100% of max. datasheet										
# B1	Bias	reverse voltage	1000 hours	138	11040	0						
		MIL-STD-750-1										
	SSOP	M1038 Method B Tj = Tjmax, Iz = 100% of max. datasheet										
# B1b	Steady State Operational	reverse current	1000 hours	20	1600	0						
# DID	Steady State Operational	Teverse current	1000 110015	20	1000	0						
	тс	JESD22-A104										
# A4	Temperature Cycling	-65 °C to Tjmax, not to exceed 150°C	1000 cycles	28	2240	0						
<i>" .</i>		JESD22-A102										
	AC	Tamb = 121 °C, RH = 100 %										
# A3 alt	Autoclave	Pressure = 205 kPa (29.7 psia)	96 hours	28	2240	0						
	H3TRB	JESD22-A101										
	High Humidity High	Tamb = 85 °C, RH = 85%, VR = 80 % of				_						
# A2 alt	Temperature Reverse Bias	<u>.                                      </u>	1000 hours	28	2240	0						
	IOL	MIL-STD-750 Method 1037										
# A5	Intermittent Operating Life	ton = toff, devices powered to insure $\Delta Tj$ = 100 °C for 15000 cycles	1000 hours	29	2320	0						
# AJ	2commetene operating the	133 C.S. 13000 Cycle3	1000 Hours	23	2320	U						
	RSH	JESD22-A111										
# C8	Resistance to Solder Heat		10 s	n.a.	n.a.	n.a.						
	SD											
# C10	Solderability	J-STD-002		63	630	0						

<sup>[1]</sup> The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Zener	11040	0	0.38	2.60E+09

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